## Notice of References Cited Application/Control No. 10/664,212 Examiner Hieu T. Hoang Applicant(s)/Patent Under Reexamination CHOI, EUN SEUK Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,062,527	06-2006	Tyrrell, III, D'Arcy M.	709/201
*	В	US-2005/0012759	01-2005	Valmiki et al.	345/629
*	С	US-6,989,836	01-2006	Ramsey, Paul R.	345/522
*	D	US-7,076,735	07-2006	Callegari, Andres C.	715/733
*	E	US-2004/0221004	11-2004	Chalfin et al.	709/203
*	F	US-2005/0104889	05-2005	Clemie et al.	345/522
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	·				
	0					
	P					
	Q					
	R					
	s					
	T				·	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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